



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): Gurtej S. Sandhu Group Art Unit: 1743  
Patent No.: 10/771,043 Examiner: Yelena Gakh  
Filed: February 3, 2004 Docket No.: 150.01150103  
Confirmation No.: 1538  
Title: DETECTION DEVICES, METHODS AND SYSTEMS FOR GAS PHASE MATERIALS

Commissioner for Patents  
Mail Stop Amendments  
P.O. Box 1450  
Alexandria, VA 22313-1450

We are transmitting the following documents along with this Transmittal Sheet (which is submitted in triplicate):


- ☒ An itemized return postcard.  
☐ A Petition for Extension of Time for \_\_\_ month(s) and a check in the amount of \$\_\_\_ for the required fee.  
☒ A Supplemental Information Disclosure Statement (2 pgs); copies of 0 applications; 1449 form (1 pg); and copies of 10 documents cited on the 1449 forms.  
☐ A check in the amount of \$\_\_\_, for \_\_\_\_.  
☐ A certified copy of a \_\_\_ application, Serial No. \_\_, filed \_\_\_\_\_, the right of priority of which is claimed under 35 U.S.C. §119.  
☐ Other:  
☐ Amendment \_\_\_ No Additional fee is required. \_\_\_ The fee has been calculated as shown:

Fee Calculation for Claims Pending After Amendment					
	Pending Claims after Amendment (1)	Claims Paid for Earlier (2)	Number of Additional Claims (1-2)	Cost per Additional Claim	Additional Fees Required
Total Claims				x \$18 =	
Independent Claims				x \$86 =	
One or More New Multiple Dependent Claims Presented? If Yes, Add \$290 Here →					
Total Additional Claim Fees Required					

Please consider this a PETITION FOR EXTENSION OF TIME for a sufficient number of months to enter these papers and please charge any additional fees or credit overpayment to Deposit Account No. 13-4895. Triplicate copies of this sheet are enclosed.

**CERTIFICATE UNDER 37 C.F.R. §1.8:** The undersigned hereby certifies that this Transmittal Letter and the paper(s), as described hereinabove, are being deposited in the United States Postal Service, as first class mail, in an envelope addressed to: Commissioner for Patents, Mail Stop Amendments, P.O. Box 1450, Alexandria, VA 22313-1450, on this 16th day of June, 2004.

MUETING, RAASCH & GEBHARDT, P.A.  
Customer Number: 26813

By:   
Kevin W. Raasch  
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(LARGE ENTITY TRANSMITTAL UNDER RULE 1.8)



PATENT  
Docket No. 150.01150103

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): Gurtej S. Sandhu	)	Group Art Unit:	1743
	)		
Serial No.: 10/771,043	)	Examiner:	Yelena Gakh
Confirmation No.: 1538	)		
	)		
Filed: February 3, 2004	)		
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For: DETECTION DEVICES, METHODS AND SYSTEMS FOR GAS PHASE MATERIALS	)		

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Mail Stop Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

In compliance with the duty imposed by 37 C.F.R. § 1.56, and in accordance with C.F.R. §§ 1.97 *et. seq.*, the materials enclosed herewith are brought to the attention of the Examiner as possibly being of interest in connection with the above-identified patent application. Per M.P.E.P. § 609, the information cited in the present Information Disclosure Statement shall not be construed to be an admission that the information is, or is considered to be, material to patentability. Consideration of each of the documents listed on the attached 1449 form is respectfully requested. As this patent application was filed after June 30, 2003, copies of the U.S. patents and U.S. patent application publications listed on the attached 1449 form have not been submitted. Pursuant to the provisions of M.P.E.P. §609, Applicant further requests that a copy of the 1449 form, marked as being considered and initialed by the Examiner, be returned with the next Official Communication.

It is believed that no fee is due, as this Information Disclosure Statement is filed prior to the receipt of any Action on the merits. However, in the event a fee is due, please charge any fee or credit any overpayment to Account No. 13-4895.

**Supplemental Information Disclosure Statement**

Page 2 of 2

Applicant(s): Gurtej S. Sandhu

Serial No.: 10/771,043

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Filed: February 3, 2004

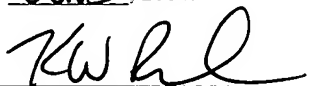
For: DETECTION DEVICES, METHODS AND SYSTEMS FOR GAS PHASE MATERIALS

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The Examiner is invited to contact Applicant's Representatives at the below-listed telephone number, if they can be of any assistance during prosecution of the present application.

**CERTIFICATE UNDER 37 C.F.R. 1.8:**

The undersigned hereby certifies that this paper is being deposited in the United States Postal Service, as first class mail, in an envelope addressed to: Mail Stop Amendment, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on this 16th day of JUNE, 2004.



Name: Kevin W. Raasch

16 JUNE 2004  
Date

Respectfully submitted for

**Gurtej S. Sandhu**

By

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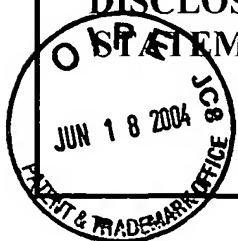
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<b>INFORMATION DISCLOSURE STATEMENT</b> 	Atty. Docket No.: 150.01150103	Serial No.: 10/771,043
	Applicant(s): Gurtej S. Sandhu	Confirmation No.: 1538
	Application Filing Date: February 3, 2004	Group: 1743
	Information Disclosure Statement mailed: June <u>16</u> , 2004	

## U.S. PATENT DOCUMENTS

Examiner Initial	Copy Enclosed	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
		5,653,807	08/05/97	Crumbaker			

## FOREIGN PATENT DOCUMENTS

Examiner Initial	Copy Enclosed	Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	X	1,576,658	08/01/69	France (w/abstract)			X	
	X	2-293644	12/04/90	Japan (w/abstract)			X	
	X	3-48748	03/01/91	Japan (w/abstract)			X	
	X	2-69658	03/08/90	Japan (w/abstract)				X

## OTHER DOCUMENTS (Including Authors, Title, Date, Pertinent Papers, etc.)

Examiner Initial	Copy Enclosed	Document Description
	X	Akinfieva, T.A., "Basis for the maximum allowable concentration of ruthenium dioxide in the air of work areas," <i>Gigiena Truda i Professional'nye Zabolevaniya</i> , 1981:46-47 (English Abstract Included)
	X	Crawford et al., "Use of the Hazop Analysis for Evaluation of CVD reactors," <i>Journal de Physique IV</i> , September 1991: C2-459- C2-466.
	X	Gale et al., "Interaction of Safety and the facility for Photovoltaic R & D," <i>American Institute of Physics Conference Proceedings</i> , 1988;66:145-151
	X	Koda et al., "Radioactivation determination of ruthenium," <i>Kyoto Daigaku Genshiro Jikkensho Gakujutsu Koenkai Koen Yoshishyu</i> , 1976;10:25-27. (English Translation)
	X	Lu et al., "Epitaxial growth of RuO <sub>2</sub> thin films by metal-organic chemical vapor deposition," <i>Thin Solid Films</i> , 1999;340:140-144.
	X	Orlow et al., "Detection of Ruthenium in Platinum Alloys," <i>Chemiker-Zeitung</i> , 1908;32:77. (English Translation)

EXAMINER	Date Considered
*Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	